June 2008

.

FAIRCHILD

SEMICONDUCTOR IM

FDW254P

P-Channel 1.8V Specified PowerTrench[®] MOSFET

General Description

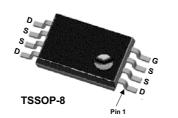
This P-Channel 1.8V specified MOSFET is a rugged gate version of Fairchild Semiconductor's advanced PowerTrench process. It has been optimized for power management applications with a wide range of gate drive voltage (1.8V – 8V).

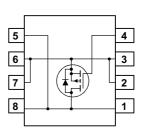
Applications

- Load switch
- Motor drive
- DC/DC conversion
- Power management

Features

- -9.2 A, -20 V. $R_{DS(ON)} = 12 \text{ m}\Omega @ V_{GS} = -4.5 \text{ V}$ $R_{DS(ON)} = 15 \text{ m}\Omega @ V_{GS} = -2.5 \text{ V}$ $R_{DS(ON)} = 21.5 \text{ m}\Omega @ V_{GS} = -1.8 \text{ V}$
- Rds ratings for use with 1.8 V logic
- Low gate charge
- High performance trench technology for extremely low R_{DS(ON)}
- Low profile TSSOP-8 package





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		-20	V
V _{GSS}	Gate-Source Voltage		±8	V
ID	Drain Current – Continuous	(Note 1)	-9.2	A
	– Pulsed		-50	
PD	Power Dissipation (N	Note 1a)	1.3	W
	1)	Note 1b)	0.6	
T_J, T_{STG}	Operating and Storage Junction Temperature F	Range	-55 to +150	°C
Therma	I Characteristics			
-			22	

ReJA Thermal Resistance, Junction-to-Ambient (Note 1a) 96 °C/W (Note 1b) 208

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
254P	FDW254P	13"	12mm	2500 units

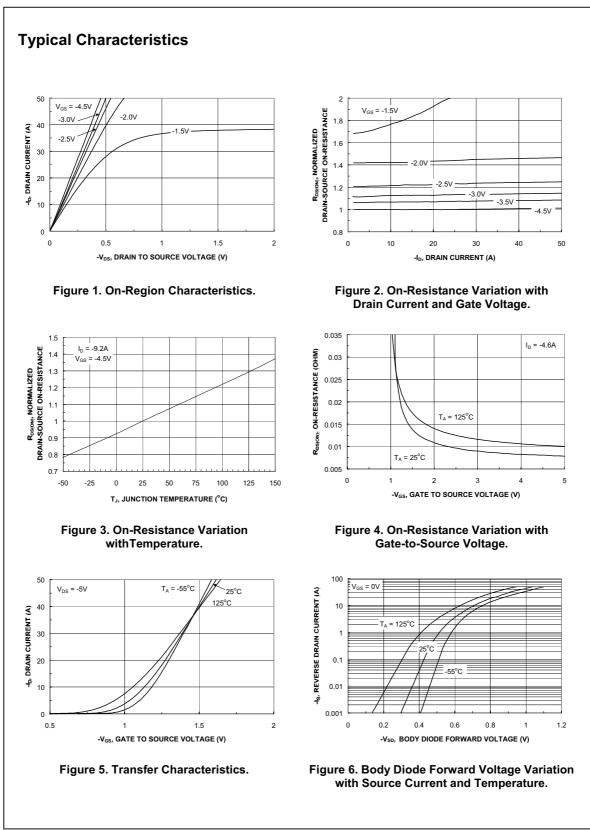
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FDW254P

racteristics		Min	Тур	Max	Units
acteristics			I		
Drain–Source Breakdown Voltage	V _{GS} = 0 V, I _D = -250 μA	-20			V
Breakdown Voltage Temperature Coefficient	I_D = -250 µA, Referenced to 25°C		-11		mV/°C
Zero Gate Voltage Drain Current	$V_{DS} = -16 V$, $V_{GS} = 0 V$			-1	μA
Gate–Body Leakage, Forward	$V_{GS} = -8 V$, $V_{DS} = 0 V$			-100	nA
Gate–Body Leakage, Reverse	V _{GS} = 8 V V _{DS} = 0 V			100	nA
	•				
Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = -250 \ \mu A$	-0.4	-0.6	-1.5	V
Gate Threshold Voltage Temperature Coefficient	$I_D = -250 \ \mu\text{A}$, Referenced to 25°C		2		mV/°C
Static Drain–Source On–Resistance	$ \begin{array}{c} V_{\rm GS} = -4.5 \ V, I_{\rm D} = -9.2 \ A \\ V_{\rm GS} = -2.5 \ V, I_{\rm D} = -7.9 \ A \\ V_{\rm GS} = -1.8 \ V, I_{\rm D} = -6.5 \ A \\ V_{\rm GS} = -4.5 \ V, \ I_{\rm D} = -9.2 \ A, \ T_{\rm J} = 125^{\circ} C \end{array} $		9 11 14 12	12 15 21.5 18	mΩ
On-State Drain Current	$V_{GS} = -4.5 V$, $V_{DS} = -5 V$	-50			Α
Forward Transconductance	$V_{DS} = -5 V$, $I_{D} = -9.2 A$		54		S
Characteristics	•				
Input Capacitance	$V_{DS} = -10 V$ $V_{CS} = 0 V$		5878		pF
Output Capacitance	f = 1.0 MHz		994		pF
Reverse Transfer Capacitance	1		559		pF
				•	
Turn–On Delay Time	$V_{DD} = -10 V$. $I_D = -1 A$.		15	27	ns
Turn–On Rise Time	$V_{GS} = -4.5 \text{ V}, R_{GEN} = 6 \Omega$	-	15	27	ns
Turn–Off Delay Time	7		210	336	ns
Turn–Off Fall Time	7		100	160	ns
Total Gate Charge	$V_{DS} = -10 V$, $I_D = -9.2 A$,		60	96	nC
Gate-Source Charge	$V_{GS} = -4.5 V$		7		nC
Gate-Drain Charge	7		13		nC
ource Diode Characteristics	and Maximum Ratings				
				-1.2	Α
Drain–Source Diode Forward Voltage	$V_{GS} = 0 V$, $I_S = -1.2 A$ (Note 2)		-0.5	-1.2	V
	Coefficient Zero Gate Voltage Drain Current Gate–Body Leakage, Forward Gate–Body Leakage, Reverse acteristics (Note 2) Gate Threshold Voltage Gate Threshold Voltage Temperature Coefficient Static Drain–Source On–Resistance On–State Drain Current Forward Transconductance Characteristics Input Capacitance Output Capacitance Reverse Transfer Capacitance g Characteristics (Note 2) Turn–On Delay Time Turn–On Rise Time Turn–Off Delay Time Turn–Off Fall Time Total Gate Charge Gate–Source Charge Gate–Drain Charge Durce Diode Characteristics	CoefficientIb $= -250 \ \mu$ A, Referenced to 25° CZero Gate Voltage Drain Current $V_{DS} = -16 \ V$, $V_{GS} = 0 \ V$ Gate-Body Leakage, Forward $V_{GS} = -8 \ V$, $V_{DS} = 0 \ V$ Gate-Body Leakage, Reverse $V_{GS} = -8 \ V$, $V_{DS} = 0 \ V$ Gate Threshold Voltage $V_{DS} = V_{GS}, \ I_D = -250 \ \mu$ AGate Threshold Voltage $I_D = -250 \ \mu$ A, Referenced to 25° CTemperature Coefficient $I_D = -250 \ \mu$ A, Referenced to 25° CStatic Drain-Source $V_{GS} = -4.5 \ V$, $I_D = -9.2 \ A$ On-Resistance $V_{GS} = -4.5 \ V$, $I_D = -9.2 \ A$ $V_{GS} = -4.5 \ V$, $I_D = -9.2 \ A$, $V_{GS} = -4.5 \ V$, $I_D = -9.2 \ A$ On-State Drain Current $V_{GS} = -4.5 \ V$, $V_{DS} = -5 \ V$ Forward Transconductance $V_{DS} = -5 \ V$, $I_D = -9.2 \ A$ Input Capacitance $V_{DS} = -5 \ V$, $I_D = -9.2 \ A$ Characteristics Input CapacitanceInput Capacitance $V_{DS} = -10 \ V$, $V_{CS} = 0 \ V$, g Characteristics (Note 2)Turn-On Delay Time $V_{DS} = -10 \ V$, $I_D = -1 \ A$,Turn-Off Delay Time $V_{DS} = -10 \ V$, $I_D = -1 \ A$,Turn-Off Fall Time $V_{DS} = -10 \ V$, $I_D = -9.2 \ A$,Gate-Source Charge $V_{DS} = -10 \ V$, $I_D = -9.2 \ A$,Gate-Drain Charge $V_{DS} = -10 \ V$, $I_D = -9.2 \ A$,Gate-Drain Charge $V_{DS} = -10 \ V$, $I_D = -9.2 \ A$,Gate-Drain Charge $V_{DS} = -10 \ V$, $I_D = -9.2 \ A$,Gate-Drain Charge $V_{DS} = -10 \ V$, $I_D = -9.2 \ A$,Gate-Drain Charge $V_{DS} = -10 \ V$, $I_D = $	CoefficientIb I_D $= -250 \mu$ A, Referenced to 25° CZero Gate Voltage Drain Current $V_{DS} = -16 V$, $V_{GS} = 0 V$ Gate-Body Leakage, Forward $V_{GS} = -8 V$, $V_{DS} = 0 V$ Gate-Body Leakage, Reverse $V_{GS} = 8 V$ $V_{DS} = 0 V$ Gate Threshold Voltage $V_{DS} = V_{GS}$, $I_D = -250 \mu$ A -0.4 Gate Threshold Voltage $I_D = -250 \mu$ A, Referenced to 25° C -0.4 Gate Threshold Voltage $I_D = -250 \mu$ A, Referenced to 25° C -0.4 Gate Threshold Voltage $I_D = -250 \mu$ A, Referenced to 25° C -0.4 Gate Threshold Voltage $I_D = -250 \mu$ A, Referenced to 25° C -0.4 Gate Threshold Voltage $I_D = -250 \mu$ A, Referenced to 25° C -0.4 Gate Threshold Voltage $I_D = -250 \mu$ A, Referenced to 25° C -0.4 Gate Threshold Voltage $V_{DS} = -4.5 V$, $I_D = -9.2 A$ $V_{CS} = -2.5 V$, $I_D = -9.2 A$ On-Resistance $V_{GS} = -4.5 V$, $V_{DS} = -5 V$ -50 Forward Transconductance $V_{DS} = -5 V$, $I_D = -9.2 A$ -50 Forward Transconductance $V_{DS} = -10 V$, $V_{CS} = 0 V$, -0.4 Output Capacitance $V_{DS} = -10 V$, $I_D = -1 A$, -0.4 Turm-On Delay Time $V_{GS} = -4.5 V$, $R_{GEN} = 6 \Omega$ -0.4 Turm-Off Delay Time $V_{DS} = -10 V$, $I_D = -9.2 A$, $-0.4 P_{CS} = -4.5 V$ Gate Charge $V_{DS} = -10 V$, $I_D = -9.2 A$, $-0.4 P_{CS} = -4.5 V$ Gate Charge $V_{DS} = -10 V$, $I_D = -9.2 A$, $-0.4 P_{CS} = -4.5 V$ Gate Charge $V_{DS} = -10 V$,	CoefficientID= -250 µA, Referenced to 25°C-11Zero Gate Voltage Drain Current $V_{DS} = -16$ V, $V_{DS} = 0$ VGate-Body Leakage, Forward $V_{GS} = -8$ V, $V_{DS} = 0$ VGate-Body Leakage, Reverse $V_{GS} = -8$ V, $V_{DS} = 0$ VGate-Body Leakage, Reverse $V_{GS} = -8$ V, $V_{DS} = 0$ VGate Threshold Voltage $V_{DS} = V_{GS}$, $I_D = -250 µA$ -0.4 -0.6 Gate Threshold Voltage $I_D = -250 µA$, Referenced to 25°C2Temperature Coefficient $I_D = -250 µA$, Referenced to 25°C2Static Drain-Source $V_{GS} = -4.5$ V, $I_D = -9.2$ A9On-Resistance $V_{GS} = -4.5$ V, $I_D = -9.2$ A, $I_J = 125°C$ 11VGS = -1.8 V, $I_D = -9.2$ A, $I_J = 125°C$ 12On-State Drain Current $V_{GS} = -4.5$ V, $V_{DS} = -5$ V -50 Forward Transconductance $V_{DS} = -5$ V, $I_D = -9.2$ A54CharacteristicsInput Capacitance $V_{DS} = -10$ V, $V_{GS} = 0$ V, 5878 Input Capacitance $f = 1.0$ MHz994Reverse Transfer Capacitance $V_{DD} = -10$ V, $I_D = -1$ A,15Turn-On Delay Time $V_{OD} = -10$ V, $I_D = -1$ A,15Turn-Off Delay Time $V_{OS} = -10$ V, $I_D = -9.2$ A,60Turn-Off Fall Time $V_{OS} = -10$ V, $I_D = -9.2$ A,60Gate-Source Charge $V_{OS} = -10$ V, $I_D = -9.2$ A,60Gate-Drain Charge $V_{OS} = -10$ V, $I_D = -9.2$ A,60Gate-Drain Charge $V_{OS} = -10$ V, $I_D = -9.2$ A,60Gate-Drain Charge $V_{OS} = -10$ V, $I_D =$	$\begin{array}{c c c c c c c c c c c c c c c c c c c $

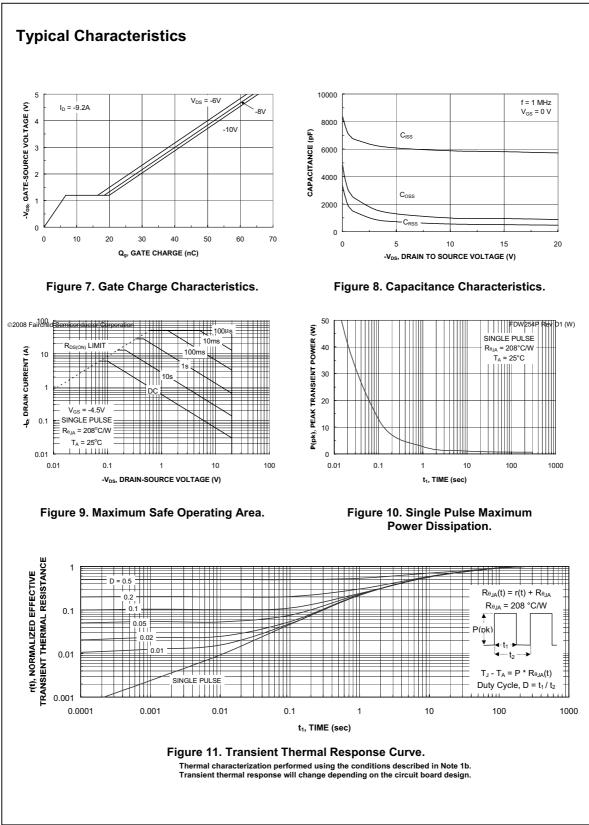
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FDW254P Rev. D1 (W)



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